





SN65LBC174A, SN75LBC174A

SLLS446G - OCTOBER 2000 - REVISED APRIL 2024

SNx5LBC174A Quadruple RS-485 Differential Line Drivers

1 Features

- Designed for TIA/EIA-485, TIA/EIA-422 and ISO 8482 applications
- Signaling Rates ¹up to 30 Mbps
- Propagation delay times < 11ns
- Low standby power consumption 1.5mA max
- Output ESD protection: 12kV
- Driver positive- and negative-current limiting
- Power-up and power-down glitch-free for line insertion applications
- Thermal shutdown protection
- Industry standard pin-out, compatible With SN75174, MC3487, DS96174, LTC487, and MAX3042

2 Applications

- Motor drives
- Factory automation and control

3 Description

SN65LBC174A SN75LBC174A The and quadruple differential line drivers with 3-state outputs. designed for TIA/EIA-485 (RS-485), TIA/EIA-422 (RS-422), and ISO 8482 applications.

These devices are optimized for balanced multipoint bus transmission at signaling rates up to 30 million bits per second. The transmission media may be printed-circuit board traces, backplanes, or cables.

The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media and the noise coupling to the environment.

Each driver features current limiting and thermalshutdown circuitry making it suitable for high-speed multipoint applications in noisy environments. These devices are designed using LinBiCMOS®, facilitating low power consumption and robustness.

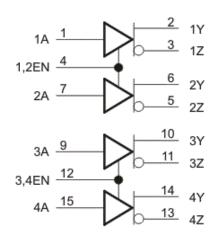
The two EN inputs provide pair-wise driver enabling, or can be externally tied together to provide enable control of all four drivers with one signal. When disabled or powered off, the driver outputs present a high-impedance to the bus for reduced system loading.

The SN75LBC174A is characterized for operation over the temperature range of 0°C to 70°C. The SN65LBC174A is characterized for operation over the temperature range of -40°C to 85°C.

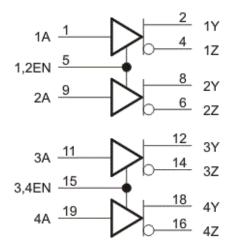
Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾
	SOIC (DW, 16)	10.3mm × 10.3mm
SN65LBC174A SN75LBC174A	SOIC (DW, 20)	12.8mm × 10.3mm
SITT OLD STITLE	PDIP (N, 16)	19.3mm × 9.4mm

- (1) For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.



Logic Diagram (Positive Logic)



Logic Diagram (Positive Logic)

¹ The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).

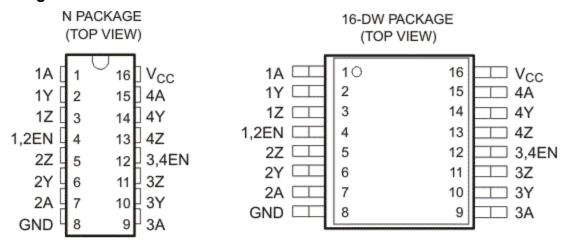


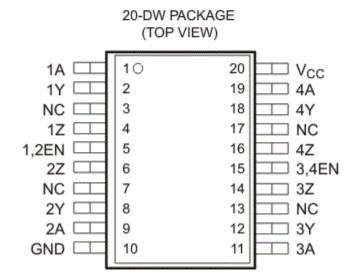
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4 Pin Configuration and Functions





5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			VALUE / UNIT	
Supply voltage range, V _{CC} ⁽²⁾			–0.3 V to 6 V	
Voltage range at ar	y bus (DC)	–10 V to 15 V		
Voltage range at ar	y bus (transient pulse through 100 Ω	–30 V to 30 V		
Input voltage range	at any A or EN terminal, V _I	–0.5 V to V _{CC} + 0.5 V		
	Lluman hadu madal (3)	Y, Z, and GND	±12 kV	
Electrostatic discharge	Human body model ⁽³⁾	All pins	±5 kV	
discriarge	Charged-device model (4)	All pins	±1 kV	
Storage temperature range, T _{stg}			−65°C to 150°C	
Continuous power dissipation			See Dissipation Rating Table	

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) All voltage values, except differential I/O bus voltages, are with respect to GND.
- (3) Tested in accordance with JEDEC standard 22, Test Method A114-A.
- (4) Tested in accordance with JEDEC standard 22, Test Method C101.

5.2 Dissipation Rating Table

Table 5-1. Dissipation Rating Table

PACKAGE ⁽¹⁾	JEDEC BOARD T _A ≤ 25°C POWER RATING		DERATING FACTOR (2) ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
16 DW	LOW K	1200 mW	9.6 mW/°C	769 mW	625 mW
IO DVV	HIGH K	2240 mW	17.9 mW/°C	1434 mW	1165 mW
20 DW	LOW K	1483 mW	11.86 mW/°C	949 mW	771 mW
20 DVV	HIGH K	2753 mW	22 mW/°C	1762 mW	1432 mW
16 N	LOW K	1150 mW	9.2 mW/°C	736 mW	598 mW

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

5.3 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT	
Supply voltage, V _{CC}		4.75	5	5.25	V	
Voltage at any bus terminal	Y, Z	-7		12	V	
High-level input voltage, V _{IH}	A. EN	2		V _{CC}		
Low-level input voltage, V _{IL}	A, EN	0		0.8	.8 V	
Output current		-60		60	mA	
Operating free-air	SN75LBC174A	0		70	°C	
temperature, T _A	SN65LBC174A	-40		85	C	

⁽²⁾ This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.



5.4 Thermal Information

		SN75ALS174A				
	THERMAL METRIC(1)	N (PDIP)	DW (SOIC)	DW	UNIT	
		16 PINS	16 PINS	20 PINS		
R _{θJA}	Junction-to-ambient thermal resistance	60.6	71.1	66.8	°C/W	
R ₀ JC(top)	Junction-to-case (top) thermal resistance	48.1	37.4	34.4	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	40.6	36.8	39.7	°C/W	
ΨЈТ	Junction-to-top characterization parameter	27.5	13.3	8.9	°C/W	
ΨЈВ	Junction-to-board characterization parameter	40.3	36.4	39	°C/W	
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	n/a	n/a	n/a	°C/W	

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



5.5 Electrical Characteristics

over recommended operating conditions

	PARAMETER	TEST CONI	DITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IK}	Input clamp voltage	I _I = -18 mA		-1.5	-0.77		V
Vo	Open-circuit output voltage	Y or Z, No load		0		V_{CC}	V
		No load (open circuit)		3		V _{CC}	
$ V_{OD(SS)} $	Steady-state differential output voltage magnitude ⁽²⁾	R_L = 54Ω, See Figure 6-1		1	1.6	2.5	V
		With common-mode loading	g, See Figure 6-2	1	1.6	2.5	
$\Delta V_{OD(SS)}$	Change in steady-state differential output voltage between logic states	See Figure 6-1	-0.1		0.1	V	
V _{OC(SS)}	Steady-state common-mode output voltage	See Figure 6-3	2	2.4	2.8	V	
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic states	See Figure 6-3	-0.02		0.02	V	
I _I	Input current	A, EN		-50		50	μΑ
	Short-circuit output current		V _I = 0V	-200		200	mA
I _{OS}	Short-circuit output current	V _{TEST} = -7V to 12V, See	V _I = V _{CC}	-200		200	
l _{OZ}	High-impedance-state output current	Figure 6-7	EN at 0V	-50		50	
I _{O(OFF)}	Output current with power off		V _{CC} = 0V	-10		10	μA
	Cumply gurrant	\/ = 0\/ or \/ No load	All drivers enabled			23	mA
I _{CC}	Supply current	$V_I = 0V$ or V_{CC} , No load			1.5	IIIA	
C	Input Canacitance	A inputs			13		pF
C _{IN}	Input Capacitance	EN inputs		21		pF	

All typical values are at V_{CC} = 5V and 25°C.

5.6 Switching Characteristics

over recommended operating conditions

PARAI	METER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high level output		5.5	8	11	ns
t _{PHL}	Propagation delay time, high-to-low level output		5.5	8	11	ns
t _r	Differential output voltage rise time		2	7.5	11	ns
t _f	Differential output voltage fall time	$R_L = 54\Omega, C_L = 50pF,$	2	7.5	11	ns
	t _{sk(p)} Pulse skew t _{PLH} - t _{PHL}	See Figure 6-4		0.6	2	
^L sk(p)				0.6	2	ns
t _{sk(o)}	Output skew ⁽¹⁾				2	ns
t _{sk(pp)}	Part-to-part skew ⁽²⁾				3	ns
t _{PZH}	Propagation delay time, high-impedance-to-high-level output	See Figure 6-5			25	ns
t _{PHZ}	Propagation delay time, high-level-output-to-high impedance	See Figure 0-5			25	ns
t _{PZL}	Propagation delay time, high-impedance-to-low-level output	See Figure 6-6			30	ns
t _{PLZ}	Propagation delay time, low-level-output-to-high impedance	See Figure 0-0			20	ns

⁽¹⁾ Output skew (t_{sk(o)}) is the magnitude of the time delay difference between the outputs of a single device with all of the inputs connected together.

⁽²⁾ The minimum V_{OD} may not fully comply with TIA/EIA-485-A at operating temperatures below 0°C. System designers should take the possibly lower output signal into account in determining the maximum signal transmission distance.

⁽²⁾ Part-to-part skew (t_{sk(pp)}) is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same input signals, the same supply voltages, at the same temperature, and have identical packages and test circuits.



5.7 Typical Characteristics

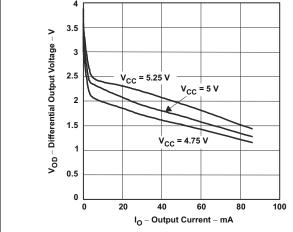


Figure 5-1. Differential Output Voltage vs Output Current

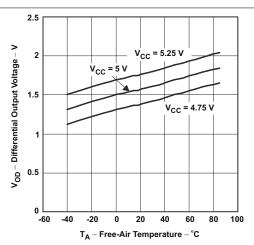


Figure 5-2. Differential Output Voltage vs Free-air Temperature

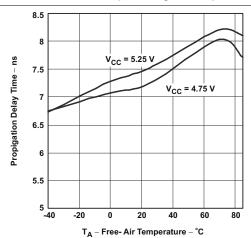


Figure 5-3. Propagation Delay Time vs Free-air Temperature

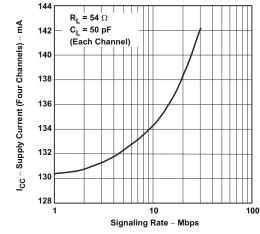
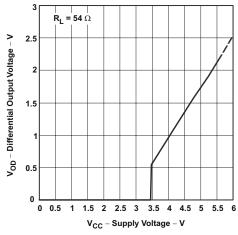
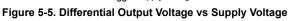


Figure 5-4. Supply Current (Four Channels) vs Signaling Rate





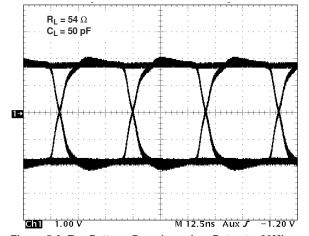


Figure 5-6. Eye Pattern, Pseudorandom Data at + 30Mbps

6 Parameter Measure Information

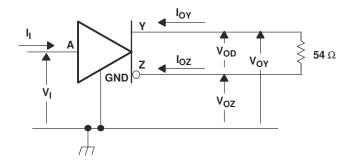


Figure 6-1. Test Circuit, V_{OD} Without Common-Mode Loading

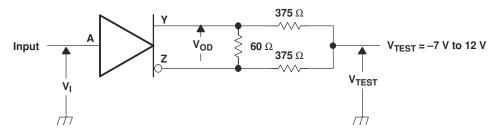
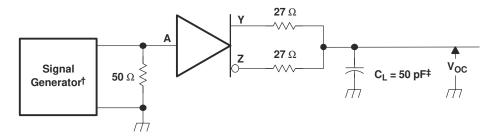
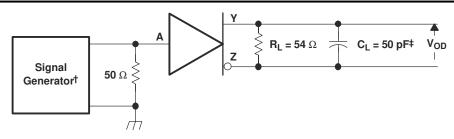


Figure 6-2. Test Circuit, V_{OD} With Common-Mode Loading



- † PRR = 1 MHz, 50% Duty Cycle, t_r < 6 ns, t_f < 6 ns, Z_O = 50 Ω
- ‡ Includes probe and jig capacitance

Figure 6-3. V_{OC} Test Circuit



- † PRR = 1 MHz, 50% Duty Cycle, t_{r} < 6 ns, t_{f} < 6 ns, Z_{O} = 50 Ω
- [‡] Includes probe and jig capacitance

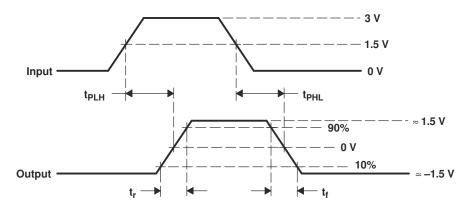
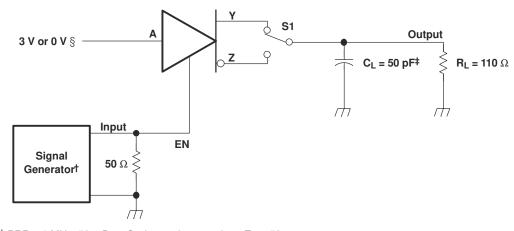


Figure 6-4. Output Switching Test Circuit and Waveforms





- † PRR = 1 MHz, 50% Duty Cycle, t_r < 6 ns, t_f < 6 ns, Z_O = 50 Ω
- ‡ Includes probe and jig capacitance
- § 3 V if testing Y output, 0 V if testing Z output

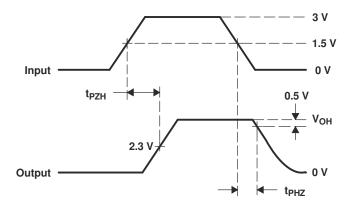
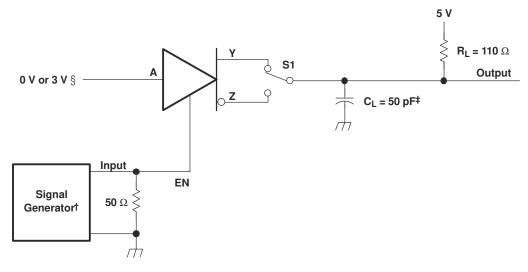


Figure 6-5. Enable Timing Test Circuit and Waveforms, t_{PZH} and t_{PHZ}



- † PRR = 1 MHz, 50% Duty Cycle, t_{r} < 6 ns, t_{f} < 6 ns, Z_{O} = 50 Ω
- ‡ Includes probe and jig capacitance
- § 3 V if testing Y output, 0 V if testing Z output

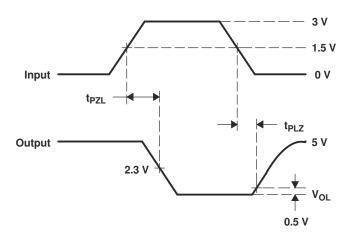


Figure 6-6. Enable Timing Test Circuit and Waveforms, t_{PZL} and t_{PLZ}



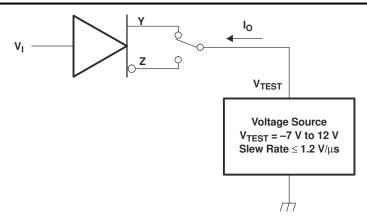


Figure 6-7. Test Circuit, Short-Circuit Output Current

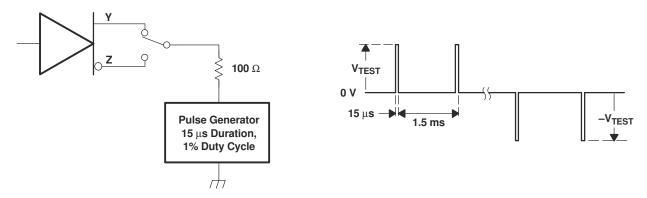


Figure 6-8. Test Circuit Waveform, Transient Overvoltage Test

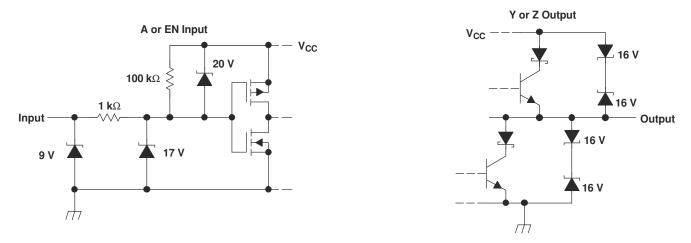


Figure 6-9. Equivalent Input and Output Schematic Diagrams



7 Device Functional Modes

Table 7-1. Function table (each driver)

INPUT ⁽¹⁾	ENABLE	OUTPUT	OUTPUT
Α	EN	Y	Z
L	Н	L	Н
Н	Н	Н	L
OPEN	Н	Н	L
L	OPEN	L	Н
Н	OPEN	Н	L
OPEN	OPEN	Н	L
Х	L	Z	Z

⁽¹⁾ H = high level, L = low level, X = irrelevant, Z = high impedance (off)



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

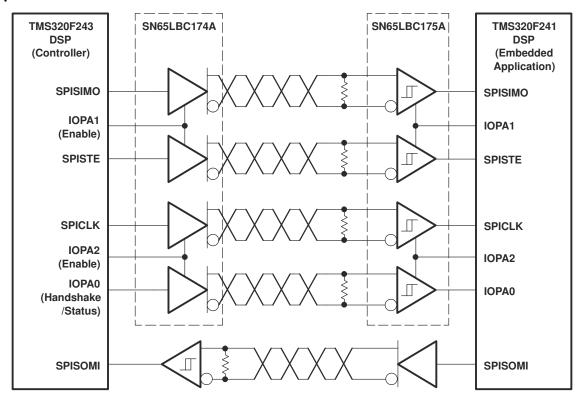


Figure 8-1. Typical Application Circuit, DSP-to-DSP Link via Serial Peripheral Interface



9 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

LinBiCMOS® is a registered trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision F (October 2009) to Revision G (April 2024)	Page
Changed the numbering format for tables, figures, and cross-references throughout the	e document1
Added the Thermal Information table	5
Changes from Revision E (July 2008) to Revision F (October 2009)	Page
Added C _{IN} - Input Capacitance to the Electrical Characteristics table	6
Changed the location of Figure 6-9	8
Changed Table 7-1 header From: ENABLE G To: ENABLE EN	13
Changes from Revision D (June 2008) to Revision E (July 2008)	Page

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Changes from Revision C (June 2008) to Revision D (July 2008)	Page
• Changed Electrostatic discharge-Human body model-Y, Z, and GND From: 13kV To:	11kV4
Changed the Dissipation Rating Table	4
Changes from Revision B (June 2001) to Revision C (May 2003)	Page
 Changed Features bullet From: Output ESD Protection Exceeds 13 kV To: Output ES 	
 Changed Features bullet for Industry Standard From: Compatible With SN75174, MC 	*
Compatible With SN75174, MC3487, DS96174, LTC487, and MAX3042	1
Changes from Revision A (February 2001) to Revision B (June 2001)	Page
Changed DW Package appearance	3
Added Figure 5-5	7
Changes from Revision * (October 2000) to Revision A (February 2001)	Page
Changed multiple items throughout the data sheet	1

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN65LBC174A16DW	LIFEBUY	SOIC	DW	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	
SN65LBC174A16DWR	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174A16DWRG4	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174ADW	LIFEBUY	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	
SN65LBC174ADWR	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174AN	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	65LBC174A	Samples
SN75LBC174A16DW	LIFEBUY	SOIC	DW	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	
SN75LBC174A16DWR	LIFEBUY	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	
SN75LBC174ADW	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174ADWR	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174AN	LIFEBUY	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	75LBC174A	

(1) The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

PACKAGE OPTION ADDENDUM

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(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN65LBC174A:

Enhanced Product: SN65LBC174A-EP

NOTE: Qualified Version Definitions:

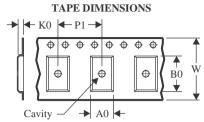
• Enhanced Product - Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LBC174A16DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
SN65LBC174ADWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN75LBC174A16DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
SN75LBC174ADWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

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*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)		
SN65LBC174A16DWR	SOIC	DW	16	2000	350.0	350.0	43.0		
SN65LBC174ADWR	SOIC	DW	20	2000	367.0	367.0	45.0		
SN75LBC174A16DWR	SOIC	DW	16	2000	350.0	350.0	43.0		
SN75LBC174ADWR	SOIC	DW	20	2000	350.0	350.0	43.0		

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN65LBC174A16DW	DW	SOIC	16	40	506.98	12.7	4826	6.6
SN65LBC174ADW	DW	SOIC	20	25	507	12.83	5080	6.6
SN65LBC174ADW	DW	SOIC	20	25	506.98	12.7	4826	6.6
SN65LBC174AN	N	PDIP	16	25	506	13.97	11230	4.32
SN75LBC174A16DW	DW	SOIC	16	40	506.98	12.7	4826	6.6
SN75LBC174ADW	DW	SOIC	20	25	507	12.83	5080	6.6
SN75LBC174ADW	DW	SOIC	20	25	506.98	12.7	4826	6.6
SN75LBC174AN	N	PDIP	16	25	506	13.97	11230	4.32

7.5 x 10.3, 1.27 mm pitch

SMALL OUTLINE INTEGRATED CIRCUIT

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.







NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
- 5. Reference JEDEC registration MS-013.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.







NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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